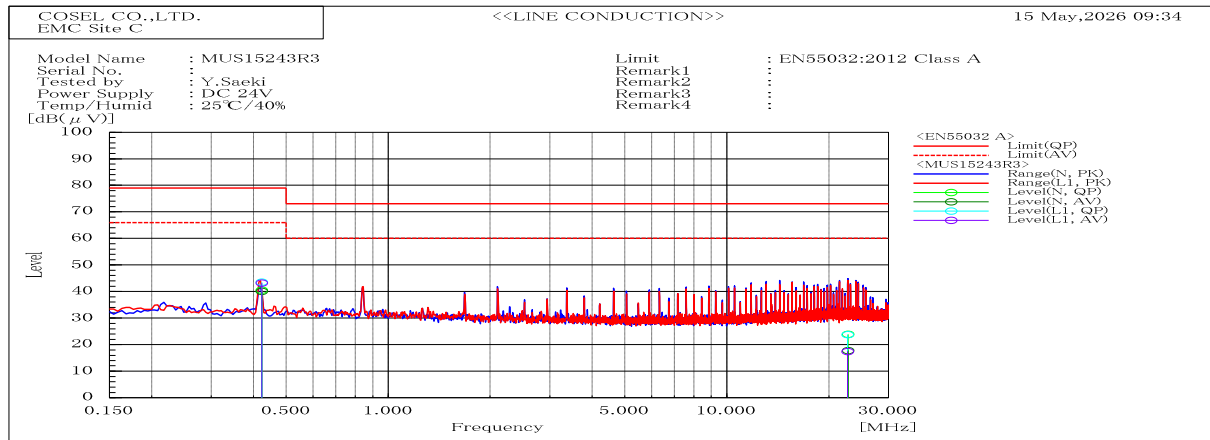
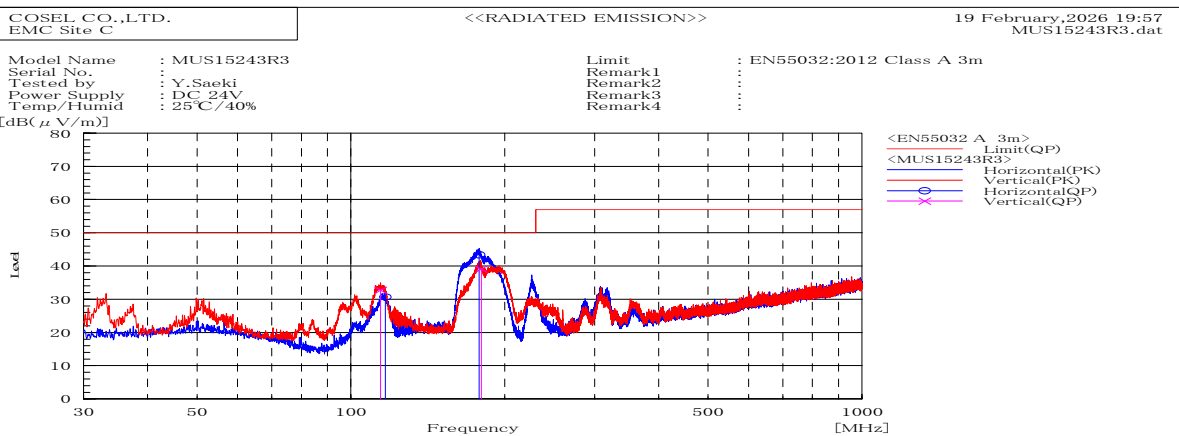


DATA SHEET		Date	15-May-26
Model	MUS15243R3	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	Y.Saeki



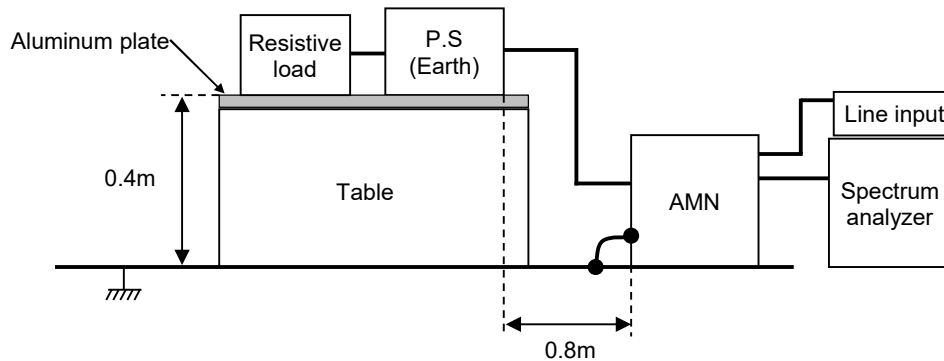
Frequency MHz	Line	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
0.423	L1	43.5	43.2	79	66	35.5	22.8	Pass	
22.729	L1	23.7	17.5	73	60	49.3	42.5	Pass	
0.423	N	40.5	40.1	79	66	38.5	25.9	Pass	
22.797	N	23.9	17.8	73	60	49.1	42.2	Pass	



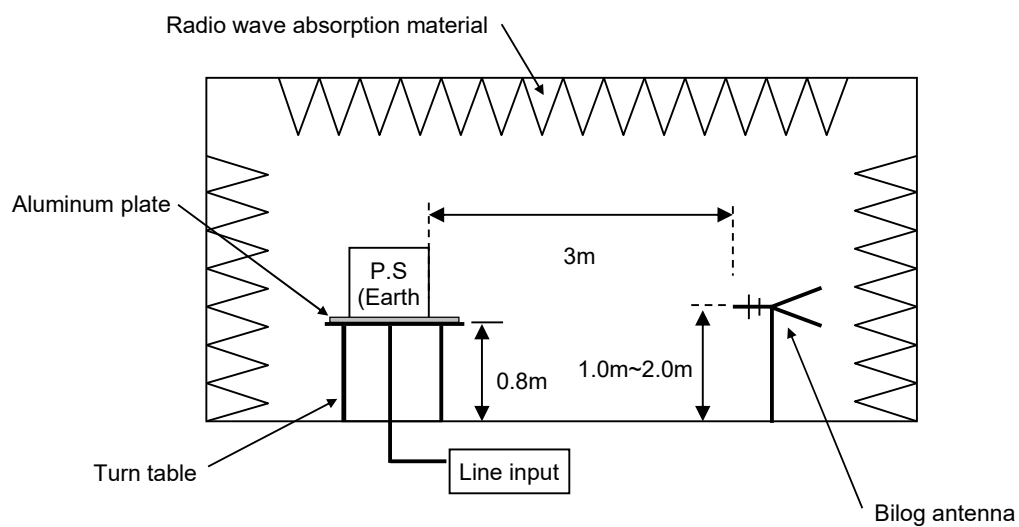
Frequency MHz	Polarization	Stability	Level dB(μV/m)		Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP	QP				
116.916	H	Stable	30.7	50	19.3	Pass	176	1.1	
178.369	H	Stable	43.4	50	6.6	Pass	200	0	
114.363	V	Stable	32.7	50	17.3	Pass	100.2	144.2	
179.972	V	Stable	39.1	50	10.9	Pass	100.2	269	

DATA SHEET		Date	15-May-26
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	Y.Saeki

1. Line conduction



2. Radiated emission



Conditions

Test : EMI
Model Name: MUS15□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

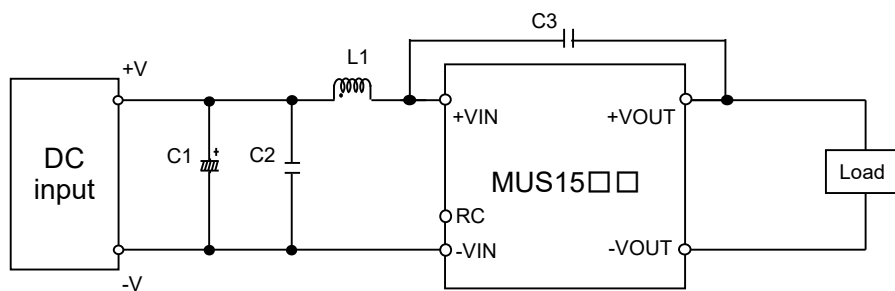


Fig.1 MUS15□□ Testing circuitry

C1 :	MUS1524□	50V 47 μ F Electric capacitor (UPWseries NICHICON)
	MUS1548□	-
C2 :	MUS1524□	50V 4.7 μ F Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MUS1548□	100V 2.2 μ F Ceramic capacitor (C3216X7S2A225KT TDK)
C3 :	MUS15□□	2000V 1000pF Ceramic capacitor (C3225X7S3D102K200AA TDK)
L1 :	MUS1524□	1600mA 22 μ H Inductor (LQH5BPN220M38 MURATA MANUFACTURING)
	MUS1548□	1100mA 47 μ H Inductor (LQH5BPN470M38 MURATA MANUFACTURING)